

ABSTRACT

An in-chip monitoring method and apparatus are disclosed. In one embodiment the apparatus includes a test pad, a transmission gate and a plurality of test components coupled to the transmission gate. The transmission gate is attached to a substrate and adapted to receive a code word uniquely addressed to one of the plurality of test components. In a further embodiment, the transmission gate is further adapted to relay an output of the one of the plurality of test components to the test pad, in response to receipt of the code word.